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| Notice of References Cited | Application/Control No. 10/658,620 | Applicant(s)/Patent Under Reexamination LIM, CHEOL WANG | |
| | Examiner Daniel G. DePumpo | Art Unit 3611 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-6,286,848 B1 | 09-2001 | Augustin, Stephan | 280/287 |
| | B | US-6,612,598 B2 | 09-2003 | Wu, Jung-Jyh | 280/270 |
| | C | US-6,161,847 A | 12-2000 | Howell et al. | 280/30 |
| | D | US-6,530,589 B1 | 03-2003 | Ma, Pei-Chuan | 280/278 |
| | E | US-6,575,486 B2 | 06-2003 | Ma, Pei-Chuan | 280/287 |
| | F | US-6,120,048 A | 09-2000 | Li, Hsing | 280/270 |
| | G | US-6,152,473 A | 11-2000 | Shih, Wen Fu | 280/278 |
| | H | US-6,431,567 B2 | 08-2002 | Tsai, Shui-Te | 280/87.041 |
| | I | US-6,609,723 B2 | 08-2003 | Chuang, A-Chueh | 280/287 |
| | J | US-4,079,957 | 03-1978 | Bleese, Wilfred J. | 280/278 |
| | K | US-5,279,181 A | 01-1994 | Boudreau, Robert J. | 74/551.1 |
| | L | US-5,553,879 A | 09-1996 | Niemeyer et al. | 280/279 |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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